PROCEEDINGS OF SPIE

MOEMS and Miniaturized Systems X

Harald Schenk Wibool Piyawattanametha Editors

24–26 January 2011 San Francisco, California, United States

Sponsored and Published by SPIE

Volume 7930

The papers included in this volume were part of the technical conference cited on the cover and title page. Papers were selected and subject to review by the editors and conference program committee. Some conference presentations may not be available for publication. The papers published in these proceedings reflect the work and thoughts of the authors and are published herein as submitted. The publisher is not responsible for the validity of the information or for any outcomes resulting from reliance thereon.

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Author(s), "Title of Paper," in MOEMS and Miniaturized Systems X, edited by Harald Schenk, Wibool Piyawattanametha, Proceedings of SPIE Vol. 7930 (SPIE, Bellingham, WA, 2011) Article CID Number.

ISSN 0277-786X ISBN 9780819484673

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445 SPIE.org

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Printed in the United States of America.

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Introduction

On behalf of the organizing and technical program committees, it is our pleasure to welcome you to the Proceedings from the 10th MOEMS and Miniaturized Systems conference which was part of the MOEMS-MEMS symposium of SPIE Photonics West 2011. Once again, the conference offered an outstanding technical program and many opportunities for stimulating discussions. We hope you were able to join and benefit personally and professionally from the meeting, sharing in the enthusiasm that makes the conference an ongoing success. The sessions provided a highly interactive forum for engineers and scientists from all around the world to present and discuss in detail recent advances in emerging technologies. Additionally, a panel discussion highlighted trends and needs for MEMS based applications. If you were unable to join, this proceedings volume will give you a sound insight into the presentations made, and thus, an overview of novel results and development activities in areas like display and imaging, microspectroscopy, scanning mirrors, micromirror arrays, MEMS for space, microendoscopy, and many others.

We want to thank our program committee for the great work they did in soliciting papers and in particular, proposing invited speakers. Special thanks go to Prof. David Dickensheets and Dr. Sonia Garcia-Blanco for the organization of the special session "MEMS-based endomicroscopy" and "Devices for space applications," respectively. Thanks to the speakers of the panel discussion, as well as to the organizers and moderator. Also, we want to thank all the session chairs for working with the authors and keeping the schedule. This conference is made possible only through the diligence and support of key individuals and supporting SPIE staff. Last but not least, we would like to thank all the authors for the technical contributions that are the heart of this conference, and to all the participants who kept discussions lively.

Harald Schenk Wibool Piyawattanametha